

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain to Source Voltage		250	V
V _{GS}	Gate to Source Voltage		±30	V
ID	Drain Current - Continuous (V _{GS} =10) (Note 1)	T _C =25°C	25.5	•
	Pulsed Drain Current	T _C = 25°C	See Figure 4	Α
E _{AS}	Single Pulse Avalanche Energy	(Note 2)	972	mJ
	Power Dissipation		417	W
P _D	Derate above 25°C		3.3	W/ºC
T _J , T _{STG}	Operating and Storage Temperature		-55 to + 150	°C
$R_{\theta JC}$	Thermal Resistance, Junction to Case		0.3	°C/W
$R_{\theta JA}$	Maximum Thermal Resistance, Junction to Ambient	(Note 3)	43	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQB27N25TM	FQB27N25TM-F085	TO-263AB	330mm	24mm	800 units
FQI27N25TU	FQI27N25TU-F085	TO-262AB	Tube	N/A	50 units

Notes:

1: Current is limited by bondwire configuration.

Starting T_J = 25°C, L = 4.67mH, I_{AS} = 20.4A, V_{DD} = 100V during inductor charging and V_{DD} = 0V during time in avalanche.
R_{θJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{θJC} is guaranteed by design while R_{θJA} is determined by the user's board design. The maximum rating presented here is based on mounting on a 1 in² pad of 2oz copper.

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Units
Off Cha	racteristics						
B _{VDSS}	Drain to Source Breakdown Voltage	I _D = 250μA, V ₀	_{GS} = 0V	250	-	-	V
I _{DSS}	Drain to Source Leakage Current	V _{DS} =250V,	T _J = 25 ^o C	-	-	1	μA
		$V_{GS} = 0V$	$T_J = 150^{\circ}C(Note 4)$	-	-	250	uA
I _{GSS}	Gate to Source Leakage Current	V _{GS} = ±30V		-	-	±100	nA
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D$ $I_D = 25.5A,$		3.0	4.1 108	5.0 131	V mΩ
On Cha	racteristics						
R _{DS(on)}	Drain to Source On Resistance		$T_{J} = 25^{\circ}C$ $T_{J} = 150^{\circ}C(Note 4)$		265	310	mΩ
Dynam i C _{iss}	c Characteristics			_	1800	-	pF
C _{oss}	Output Capacitance	$-V_{DS} = 25V, V_{C}$	_{BS} = 0V,	-	350	-	pF
C _{rss}	Reverse Transfer Capacitance	f = 1MHz		-	45	-	pF
R _g	Gate Resistance	f = 1MHz		-	0.82	-	Ω
Q _{g(ToT)}	Total Gate Charge at 10V	V _{GS} = 0 to 10 ⁴	✓ V _{DD} = 125∨	-	45	49	nC
Q _{g(th)}	Threshold Gate Charge	V_{GS} = 0 to 2V	I _D = 27A	-	3.3	4	nC
Q _{gs}	Gate to Source Gate Charge			-	12	-	nC
	Gate to Drain "Miller" Charge		-		23		nC

Switching Characteristics

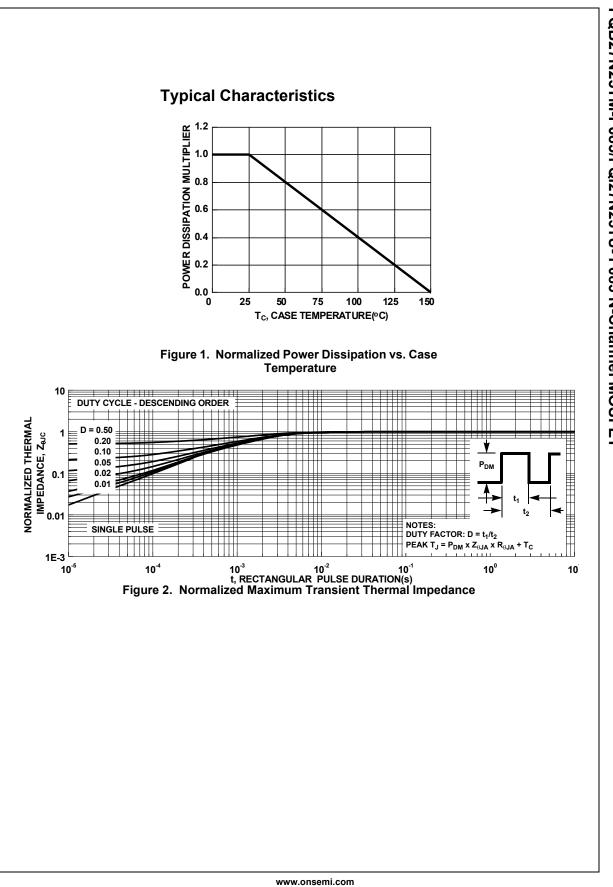
t _{on}	Turn-On Time		-	-	196	ns
t _{d(on)}	Turn-On Delay		-	36	-	ns
t _r	Rise Time	V _{DD} = 125V, I _D = 27A,	-	122	-	ns
t _{d(off)}	Turn-Off Delay	V _{DD} = 125V, I _D = 27A, V _{GS} = 10V, R _{GEN} = 25Ω	-	81	-	ns
t _f	Fall Time		-	60	-	ns
t _{off}	Turn-Off Time		-	-	164	ns

Drain-Source Diode Characteristics

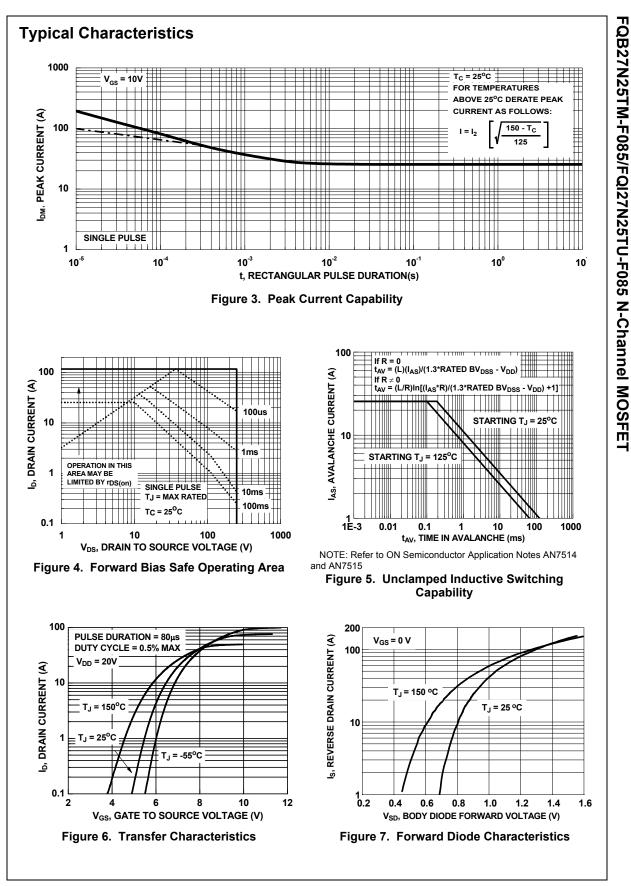
Van	Source to Drain Diode Voltage	I _{SD} = 25.5A, V _{GS} = 0V	-	-	1.5	V
V _{SD}	Source to Drain Diode voltage	I _{SD} = 12.75A, V _{GS} = 0V	-	-	1.25	V
t _{rr}	ReverseRecovery Time	I _F = 27A, dI _{SD} /dt = 100A/μs,	-	205	238	ns
Q _{rr}	ReverseRecovery Charge	V _{DD} =200V	-	1.8	2.3	nC

Notes:

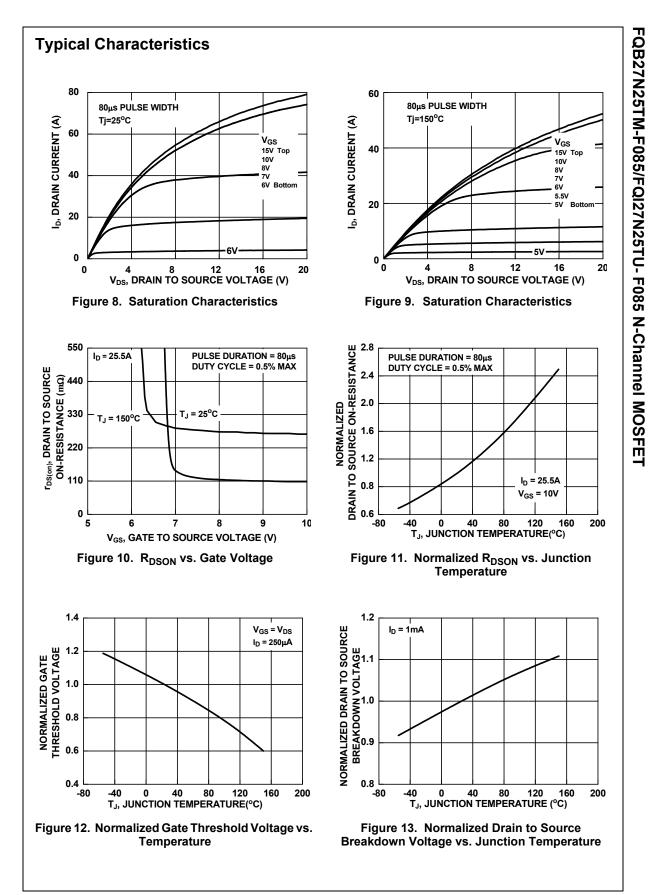
4: The maximum value is specified by design at T_J = 150°C. Product is not tested to this condition in production.



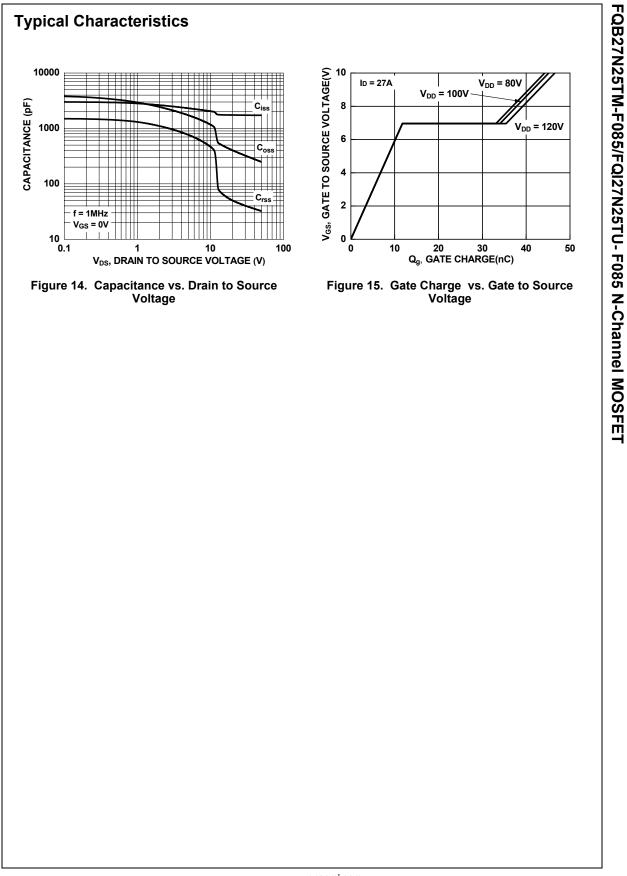
FQB27N25TM-F085/FQI27N25TU- F085 N-Channel MOSFET



www.onsemi.com 4



www.onsemi.com 5



ON Semiconductor and are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at <u>www.onsemi.com/site/pdf/Patent-Marking.pdf</u>. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor haves, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such uninten

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800–282–9855 Toll Free USA/Canada Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910

Japan Customer Focus Center Phone: 81–3–5817–1050 ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative